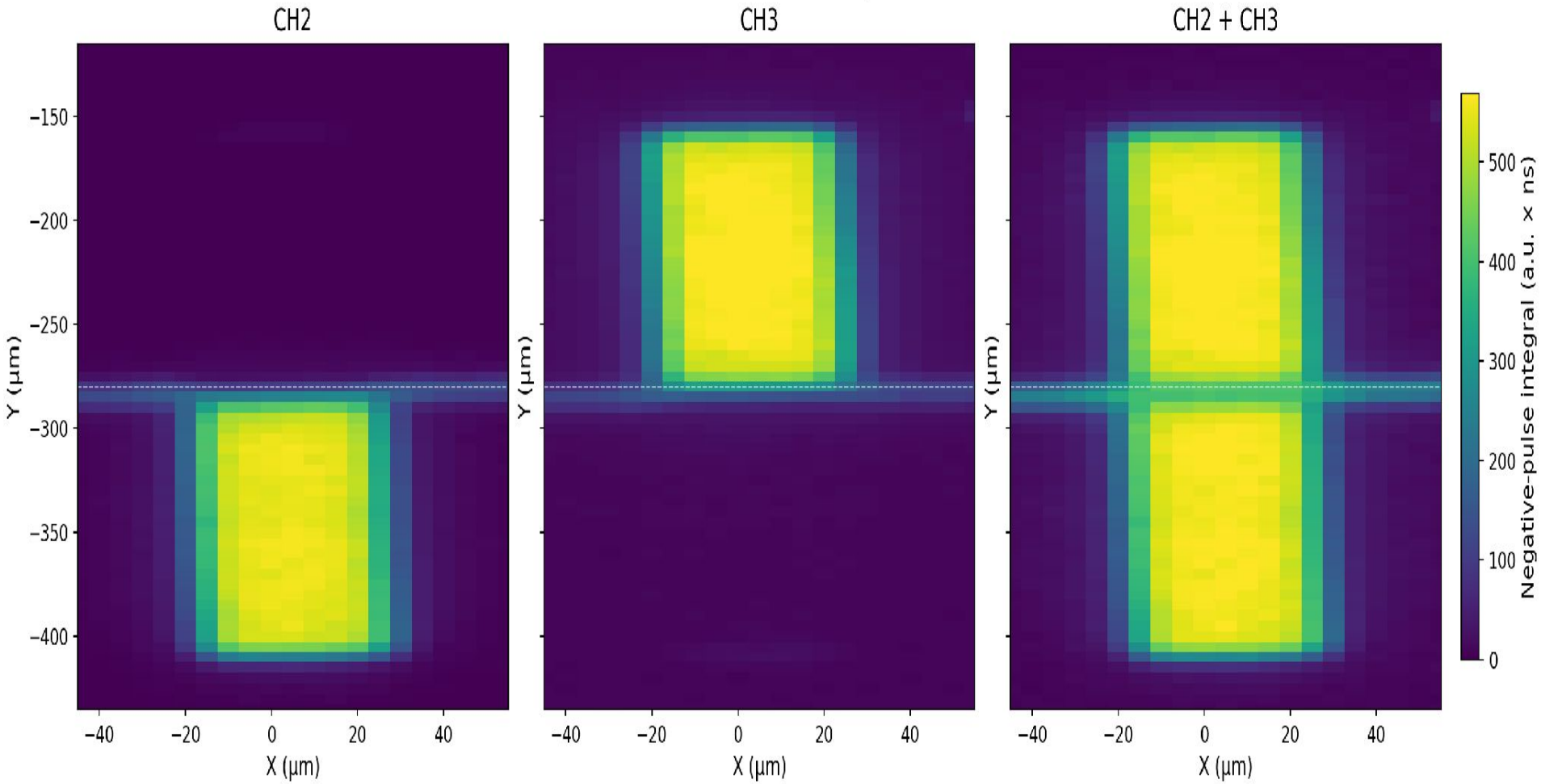
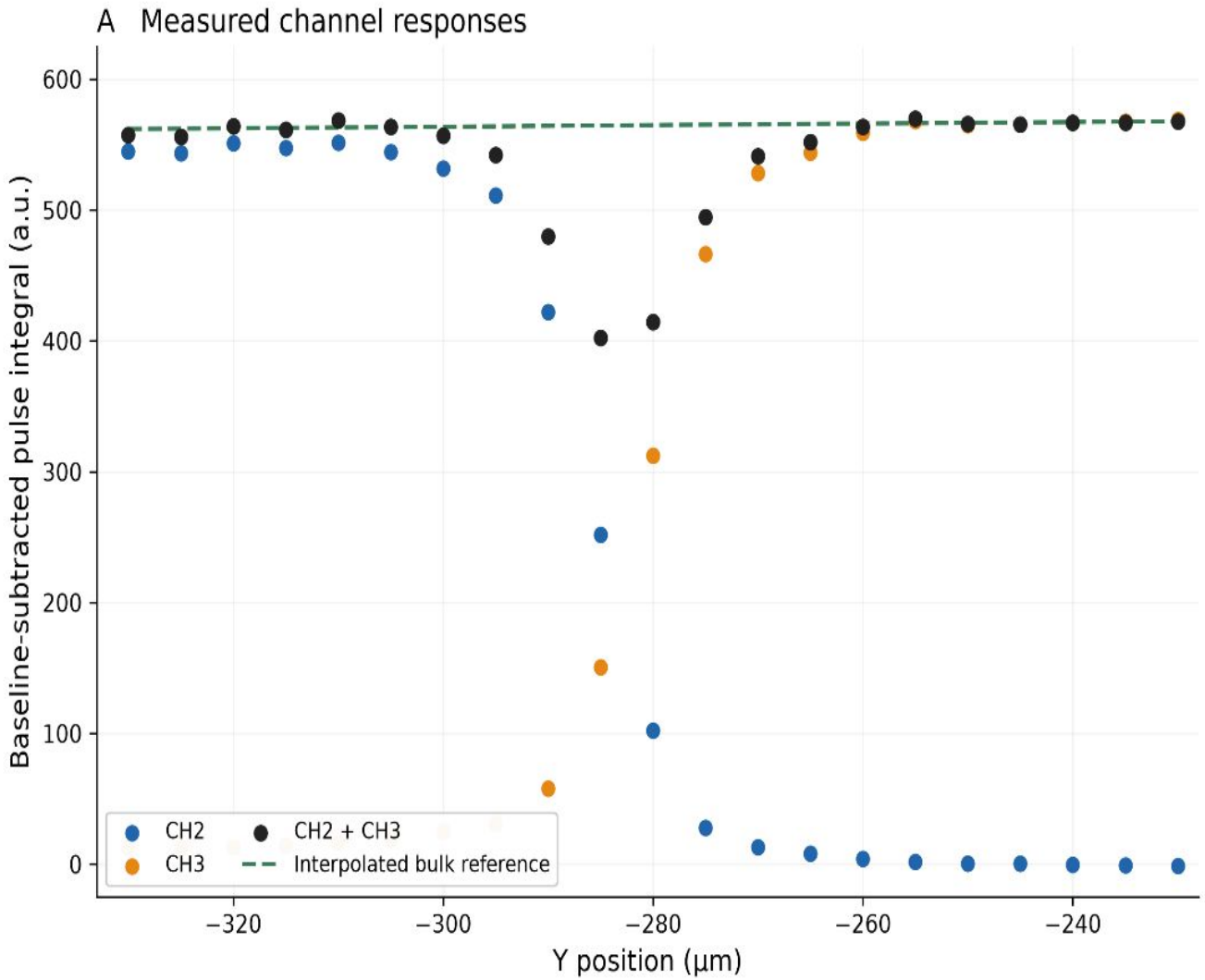
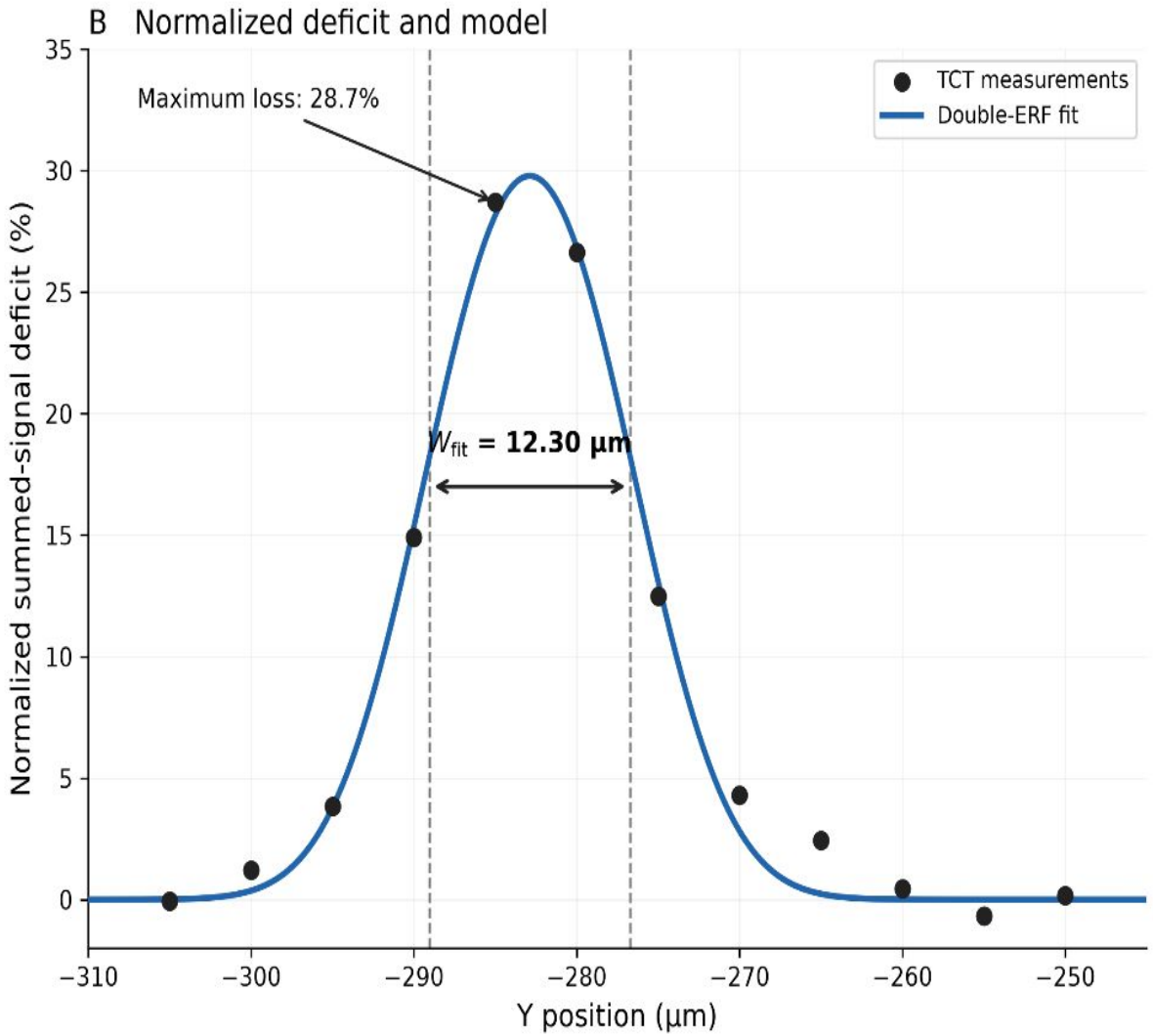
IR laser scan of TI-LGAD (wafer 11, TW 4/6) @ 100 V







Maximum measured deficit: 28.7%
Fitted analogue-response width: 12.3 µm @ 100 V